

Notice of References Cited	Application/Control No. 10/822,884	Applicant(s)/Patent Under Reexamination YIP ET AL.	
	Examiner Tanh Q. Nguyen	Art Unit 2182	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,318,632 B1	11-2001	Grant et al.	235/441
*	B	US-2004/0113129 B1	06-2004	Waggoner et al.	252/500
*	C	US-2006/0235154 B1	10-2006	Miara et al.	525/178
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-297946	11-1996	JP	Miyashita et al.	G11B 23/03
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.